54F/74F410 Register Stack—16 x 4 RAM TRI-STATE Output Register

# 54F/74F410 Register Stack—16 x 4 RAM TRI-STATE® Output Register

### **General Description**

The 'F410 is a register-oriented high-speed 64-bit Read/ Write Memory organized as 16-words by 4-bits. An edgetriggered 4-bit output register allows new input data to be written while previous data is held. TRI-STATE outputs are provided for maximum versatility. The 'F410 is fully compatible with all TTL families.

### **Features**

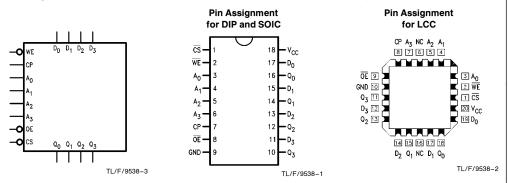
- Edge-triggered output register
- Typical access time of 35 ns
- TRI-STATE outputs
- Optimized for register stack operation
- 18-pin package
- 9410 replacement

Commercial	Military	Package Number	Package Description
74F410PC		N18A	18-Lead (0.300" Wide) Molded Dual-In-Line
	54F410DM (Note 1)	J18A	18-Lead Ceramic Dual-In-Line
74F410SC		M20B	20-Lead (0.300" Wide) Molded Small Outline, JEDEC
54F410LM		W20A	20-Lead Cerpak

Note 1: Military grade device with environmental and burn-in processing. Use suffix = DMQB, LMQB

### **Logic Symbol**

### **Connection Diagrams**



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### **Unit Loading/Fan Out**

		54F/74F				
Pin Names	Description	U.L. HIGH/LOW	Input I <sub>IH</sub> /I <sub>IL</sub> Output I <sub>OH</sub> /I <sub>OL</sub>			
A <sub>0</sub> -A <sub>3</sub>	Address Inputs	1.0/1.0	20 μA/ - 0.6 mA			
D <sub>0</sub> -D <sub>3</sub>	Data Inputs	1.0/1.0	20 μA/ - 0.6 mA			
CS	Chip Select Input (Active LOW)	1.0/2.0	20 μA/ – 1.2 mA			
ŌĒ	Output Enable Input (Active LOW)	1.0/1.0	20 μA/ - 0.6 mA			
WE	Write Enable Input (Active LOW)	1.0/1.0	20 μA/ - 0.6 mA			
CP	Clock Input (Outputs Change on		,			
	LOW-to-HIGH Transition)	1.0/2.0	20 μA/ – 1.2 mA			
Q <sub>0</sub> -Q <sub>3</sub>	TRI-STATE Outputs	150/40 (33.3)	-3 mA/24 mA (20 mA)			

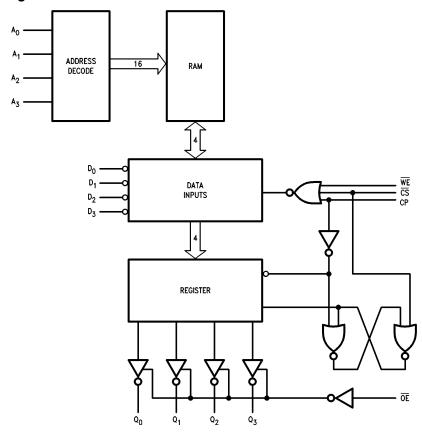
### **Functional Description**

**Write Operation**—When the three control inputs, Write Enable ( $\overline{WE}$ ), Chip Select ( $\overline{CS}$ ), and Clock (CP), are LOW the information on the data inputs ( $D_0-D_3$ ) is written into the memory location selected by the address inputs ( $A_0-A_3$ ). If the input data changes while  $\overline{WE}$ ,  $\overline{CS}$ , and CP are LOW, the contents of the selected memory location follow these changes, provided setup and hold time criteria are met.

**Read Operation**—Whenever  $\overline{CS}$  is LOW and CP goes from LOW-to-HIGH, the contents of the memory location selected by the address inputs (A<sub>0</sub>-A<sub>3</sub>) are edge-triggered into the Output Register.

The  $(\overline{OE})$  input controls the output buffers. When  $\overline{OE}$  is HIGH the four outputs  $(Q_0-Q_3)$  are in a high impedance or OFF state; when  $\overline{OE}$  is LOW, the outputs are determined by the state of the Output Register.

### **Block Diagram**



TL/F/9538-4

### **Absolute Maximum Ratings** (Note 1)

If Military/Aerospace specified devices are required, please contact the National Semiconductor Sales Office/Distributors for availability and specifications.

 $\begin{array}{lll} \mbox{Storage Temperature} & -65^{\circ}\mbox{C to} + 150^{\circ}\mbox{C} \\ \mbox{Ambient Temperature under Bias} & -55^{\circ}\mbox{C to} + 125^{\circ}\mbox{C} \\ \mbox{Junction Temperature under Bias} & -55^{\circ}\mbox{C to} + 175^{\circ}\mbox{C} \\ \mbox{Plastic} & -55^{\circ}\mbox{C to} + 150^{\circ}\mbox{C} \\ \end{array}$ 

V<sub>CC</sub> Pin Potential to

Ground Pin -0.5V to +7.0V Input Voltage (Note 2) -0.5V to +7.0V Input Current (Note 2) -30 mA to +5.0 mA

Voltage Applied to Output in HIGH State (with  $V_{CC} = 0V$ )

 $\begin{array}{lll} \text{Standard Output} & -0.5 \text{V to V}_{\text{CC}} \\ \text{TRI-STATE Output} & -0.5 \text{V to } +5.5 \text{V} \end{array}$ 

Current Applied to Output

in LOW State (Max) twice the rated I<sub>OL</sub> (mA)

**Note 1:** Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

Note 2: Either voltage limit or current limit is sufficient to protect inputs.

# Recommended Operating Conditions

Free Air Ambient Temperature

Military  $-55^{\circ}\text{C to} + 125^{\circ}\text{C}$ Commercial  $0^{\circ}\text{C to} + 70^{\circ}\text{C}$ 

Supply Voltage

Military + 4.5V to + 5.5V Commercial + 4.5V to + 5.5V

### **DC Electrical Characteristics**

Symbol	Parameter -		54F/74F			Units	Vcc	Conditions	
Symbol			Min	Тур	Max	Units	VCC	Conditions	
V <sub>IH</sub>	Input HIGH Voltage		2.0			٧		Recognized as a HIGH Signal	
$V_{IL}$	Input LOW Voltage				0.8	V		Recognized as a LOW Signal	
V <sub>CD</sub>	Input Clamp Diode Vo	oltage			-1.2	V	Min	$I_{\text{IN}} = -18  \text{mA}$	
V <sub>OH</sub>	Output HIGH Voltage	54F 10% V <sub>CC</sub> 54F 10% V <sub>CC</sub> 74F 10% V <sub>CC</sub> 74F 10% V <sub>CC</sub> 74F 5% V <sub>CC</sub>	2.5 2.4 2.5 2.4 2.7			V	Min	$\begin{split} I_{OH} &= -1 \text{ mA} \\ I_{OH} &= -3 \text{ mA} \\ I_{OH} &= -1 \text{ mA} \\ I_{OH} &= -3 \text{ mA} \\ I_{OH} &= -3 \text{ mA} \end{split}$	
V <sub>OL</sub>	Output LOW Voltage	54F 10% V <sub>CC</sub> 74F 10% V <sub>CC</sub>			0.5 0.5	٧	Min	$I_{OL} = 20 \text{ mA}$ $I_{OL} = 24 \text{ mA}$	
I <sub>IH</sub>	Input HIGH Current	54F 74F			20.0 5.0	μΑ	Max	V <sub>IN</sub> = 2.7V	
I <sub>BVI</sub>	Input HIGH Current Breakdown Test	54F 74F			100 7.0	μΑ	Max	V <sub>IN</sub> = 7.0V	
I <sub>CEX</sub>	Output HIGH Leakage Current	54F 74F			250 50	μΑ	Max	$V_{OUT} = V_{CC}$	
V <sub>ID</sub>	Input Leakage Test	74F	4.75			٧	0.0	$I_{\text{ID}} = 1.9 \ \mu\text{A}$ All Other Pins Grounded	
I <sub>OD</sub>	Output Leakage Circuit Current	74F			3.75	μΑ	0.0	V <sub>IOD</sub> = 150 mV All Other Pins Grounded	
I <sub>IL</sub>	Input LOW Current				-0.6 -1.2	mA	Max	$V_{IN} = 0.5V (A_n, D_n, \overline{OE}, \overline{WE})$ $V_{IN} = 0.5V (\overline{CS}, CP)$	
lozh	Output Leakage Current				50	μΑ	Max	$V_{OUT} = 2.7V$	
l <sub>OZL</sub>	Output Leakage Current				-50	μΑ	Max	V <sub>OUT</sub> = 0.5V	
los	Output Short-Circuit Current		-60		<b>-150</b>	mA	Max	$V_{OUT} = 0V$	
I <sub>ZZ</sub>	Bus Drainage Test				500	μΑ	0.0V	V <sub>OUT</sub> = 5.25V	

### DC Electrical Characteristics (Continued)

Symbol	Parameter		54F/74F		Units	v <sub>cc</sub>	Conditions	
	Farameter	Min	Тур	Max	Office	VCC		
Іссн	Power Supply Current		47	70	mA	Max	V <sub>O</sub> = HIGH	
Iccl	Power Supply Current		47	70	mA	Max	$V_O = LOW$	
Iccz	Power Supply Current		47	70	mA	Max	V <sub>O</sub> = HIGH Z	

### **AC Electrical Characteristics**

Symbol		7-	4F	5	4F	7		
	Parameter	$egin{array}{ll} T_{ extsf{A}} = \ +25^{\circ} extsf{C} \ V_{ extsf{CC}} = \ +5.0 extsf{V} \ C_{ extsf{L}} = \ 50  ext{ pF} \end{array}$		extstyle  ext		T <sub>A</sub> , V <sub>CC</sub> = Com C <sub>L</sub> = 50 pF		Units
		Min	Max	Min	Max	Min	Max	
t <sub>PLH</sub>	Propagation Delay CP to Q	3.0 3.5	8.5 9.0	2.5 3.0	11.0 12.0	2.5 3.0	9.5 10.0	ns
t <sub>PZH</sub>	Enable Time OE to Q	3.0 3.5	8.0 9.0	2.5 3.0	10.5 13.0	2.5 3.0	9.0 10.0	
t <sub>PHZ</sub>	Disable Time OE to Q	2.5 2.5	6.5 7.0	2.0 2.0	8.5 9.5	2.0 2.0	7.5 8.0	ns

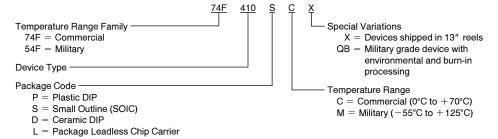
## **AC Operating Requirements**

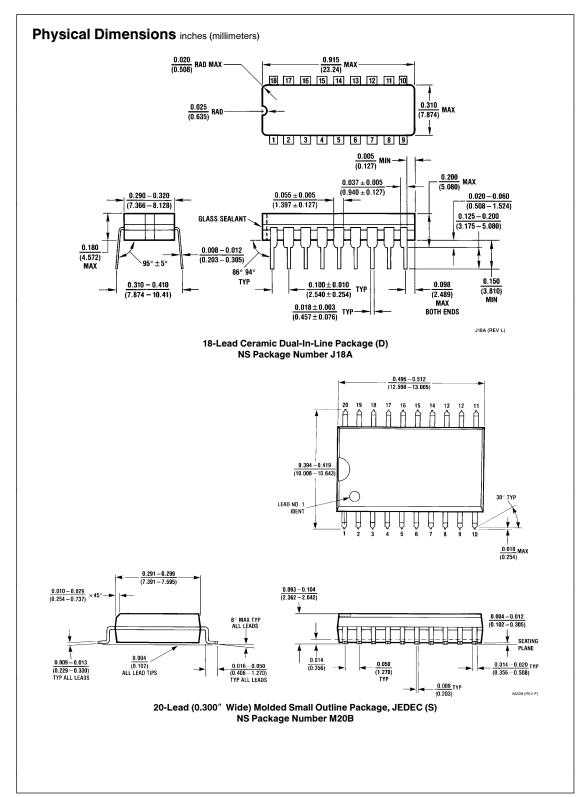
Symbol		74F		54	F	74F  T <sub>A</sub> , V <sub>CC</sub> = Com		Units
	Parameter		+ 25°C + 5.0V	$T_A, V_{CC} = Mil$				
		Min	Max	Min	Max	Min	Max	
READ MODE	E							
t <sub>s</sub> (H) t <sub>s</sub> (L)	Setup Time, HIGH or LOW A <sub>n</sub> to CP	15.0 15.0		23 23		17.0 17.0		
t <sub>h</sub> (H)	Hold Time, HIGH or LOW A <sub>n</sub> to CP	0 0		0		0		ns
WRITE MOD	DE							
t <sub>s</sub> (H) t <sub>s</sub> (L)	Setup Time, HIGH or LOW A <sub>n</sub> to WE	0 0		0		0		
t <sub>h</sub> (H)	Hold Time, HIGH or LOW A <sub>n</sub> to WE	0 0		0		0		ns
t <sub>s</sub> (H)	Setup Time, HIGH or LOW D <sub>n</sub> to WE	5.0 5.0		8.5 8.5		6.0 6.0		
t <sub>h</sub> (H)	Hold Time, HIGH or LOW D <sub>n</sub> to WE	0 0		2.5 2.5		0		ns
t <sub>w</sub>	WE Pulse Width Required to Write	7.5		9.5		8.5		ns
t <sub>w</sub>	CS Pulse Width Required to Write	7.5		9.5		8.5		ns
t <sub>w</sub>	CP Pulse Width Required to Write	7.5		9.5		8.5		ns

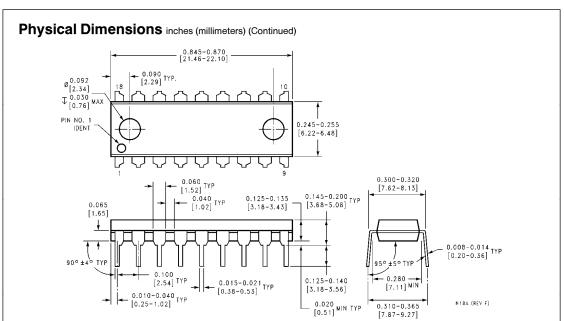
Note: Military temperature range for this device is  $-40^{\circ}\text{C}$  to  $+85^{\circ}\text{C}.$ 

### **Ordering Information**

The device number is used to form part of a simplified purchasing code where a package type and temperature range are defined as follows:

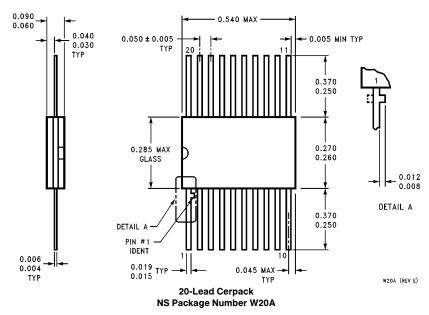






18-Lead (0.300" Wide) Molded Dual-In-Line Package (P)
NS Package Number N18A

### Physical Dimensions inches (millimeters) (Continued)



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